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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/027,657	MEYER ET AL.	
Examiner	Art Unit	
Jia Lu	2611	

	SEARCHED			
Class	Subclass	Date	Examiner	
375	347	1/18/2007	JL	
375	346	1/18/2007	JL	
370	442	1/18/2007	JL	
370	480	1/18/2007	JL	
370	347	1/18/2007	JL	
375	344	1/18/2007	JL	

INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
ALL EAST DATABASES	1/18/2007	JL	